

Notice of References Cited	Application/Control No. 09/877,906		Applicant(s)/Patent Under Reexamination KIM, HYEON-SEAG	
	Examiner Douglas W Owens		Art Unit 2811	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,880,508	03-1999	Wu, Shye-Lin	257/411
X	B	US-6,353,259	03-2002	Sato et al.	257/369
X	C	US-6,368,907	04-2002	Doi et al.	438/217
X	D	US-6,406,945	06-2002	Lee et al.	438/142
X	E	US-6,362,065	03-2002	Swanson et al.	438/344
X	F	US-6,406,973	06-2002	Lee, Jung Ho	438/416
X	G	US-2001/0020723	09-2001	GARDNER et al.	257/368
X	H	US-2002/0014662	02-2002	Yamazaki et al.	257/347
	I	US-6,255,698 /	07-2001	Gardner et al.	257/369
	J	US-6,353,249 /	03-2002	Boyd et al.	257/369
	K	US-6,373,114 /	04-2002	Jeng et al.	257/413
	L	US-6,483,151	11-2002	Wakabayashi et al.	257/369
	M	US-2002/0000607 /	01-2002	Pfirsch, Frank	257/328

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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